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FORM PTO-1449	SERIAL NO.	CASE NO.
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LIST OF PATENTS AND PUBLICATIONS FOR	FILING DATE	GROUP ART UNIT
APPLICANT'S INFORMATION DISCLOSURE STATEMENT	October 24, 2003	1755
(use several sheets if necessary)	APPLICANT(S): Nixon et al.	

 Number-Kind Code (if known)	DATE	NAME	SUBCLASS	FILING DATE
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FOREIGN PATENT DOCUMENTS EXAMINER DOCUMENT TRANSLATION YES OR NO CLASS/ INITIAL **SUBCLASS NUMBER** COUNTRY DATE Number-Kind Code (if known) **B**1 2000-256064 9/19/00 Japan Yes KEG (translation)

EXAMINER INITIAL	OTHER ART — NON PATENT LITERATURE DOCUMENTS (Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.
KEG	B2 Vijay Vasant Pujar, Processing and Microstructural Characterization of Reaction-Formed Silicon Carbide (RFSC) and Computer Simulations, X-Ray Diffraction and High Resolution Transmission Electron Microscopy of Stacking Faults in β-SiC, Case Western Reserve University Dissertation, January 1997, pp. 38-51

EXAMINER		DATE CONSIDERED	
EVO WILLIAE I	/Karl Group/	I DATE CONSIDERED	05/03/0006
	/ Marr Group/		05/23/2006
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